

Applicant(s)/Patent Under
Reexamination
NAGAI ET AL.

Examiner

Jean E Lesperance

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,118,425	09-2000	Kudo et al.	345/100
	В	US-			
	С	US-			
	D	US-			
	Ε	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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